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APPLICATION NO.			FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/600,667			Damon Genetti	10001.001800 (NVLS 795)	
31894	7590	10/20/2004	EXAMINER		NER
OKAMOT	O & BEN	VEDICTO, LLP	MARC, MCDIEUNEL		
P.O. BOX 6	41330				
SAN JOSE, CA 95164				ART UNIT	PAPER NUMBER
				3661	

DATE MAILED: 10/20/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

		Applica	tion No.	Applicant(s)					
		10/600,	667	GENETTI ET AL.	\mathcal{G}				
	Office Action Summary	Examin	er	Art Unit					
		McDieur	nel Marc	3661					
Period fo	The MAILING DATE of this communic	cation appears on t	he cover sheet with the	correspondence add	ress				
A SH THE - Exte after - If the - If NC - Failu Any	ORTENED STATUTORY PERIOD FO MAILING DATE OF THIS COMMUNIO nsions of time may be available under the provisions of SIX (6) MONTHS from the mailing date of this commuse period for reply specified above is less than thirty (30) period for reply is specified above, the maximum state are to reply within the set or extended period for reply we reply received by the Office later than three months afted patent term adjustment. See 37 CFR 1.704(b).	CATION. f 37 CFR 1.136(a). In no on inication. I days, a reply within the study period will apply and rill, by statute, cause the a	event, however, may a reply be atutory minimum of thirty (30) o will expire SIX (6) MONTHS fro oplication to become ABANDO	timely filed days will be considered timely, on the mailing date of this con NED (35 U.S.C. § 133).	nmunication.				
Status									
1)⊠	Responsive to communication(s) filed	l on <u>26 September</u>	<u>2003</u> .						
2a) <u></u> ☐	This action is FINAL .	o)⊠ This action is	non-final.						
3)□	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.								
Disposit	ion of Claims								
5)⊠ 6)⊠ 7)⊠	 ✓ Claim(s) 1-20 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. ✓ Claim(s) 16-20 is/are allowed. ✓ Claim(s) 1,2,6-10,12,14 and 15 is/are rejected. ✓ Claim(s) 3-5,11 and 13 is/are objected to. ✓ Claim(s) are subject to restriction and/or election requirement. 								
Applicat	ion Papers								
· ·	The specification is objected to by the The drawing(s) filed on is/are:		objected to by the	e Evaminer					
. • ,	Applicant may not request that any object		•						
11)	Replacement drawing sheet(s) including the oath or declaration is objected to	he correction is requ	ired if the drawing(s) is	objected to. See 37 CFF					
Priority (under 35 U.S.C. § 119								
12) <u>□</u> a)	Acknowledgment is made of a claim for All b) Some * c) None of: 1. Certified copies of the priority of Some * Copies of the priority of Some * Copies of the priority of Some * Copies of the certified copies of the attached detailed Office action	ocuments have be ocuments have be f the priority docun al Bureau (PCT Ri	en received. en received in Applica nents have been recei ule 17.2(a)).	ation No ived in this National S	itage				
Attachmen	• •		4)	(DTO 442)					
2) 🔲 Notic 3) 🔯 Infor	ee of References Cited (PTO-892) te of Draftsperson's Patent Drawing Review (PT mation Disclosure Statement(s) (PTO-1449 or F er No(s)/Mail Date <u>9/26/03</u> .		4) Interview Summa Paper No(s)/Mail 5) Notice of Informa 6) Other:		152)				

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DETAILED ACTION

1. Claims 1-20 are allowed.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1-2, 6-10, 12, 14 and 15 are rejected under 35 U.S.C. 102(b) as being anticipated by **Lento**.

As per claim 1-2, 6-10, 12, 14 and 15, <u>Lento</u> teaches "Wafer Handling And Fab Automation: Using and integrated controller to manage wafer-handling systems" including a method of automatically calibrating a wafer-handling robot (see page 4, col. 2, 3rd paragraph), the method Comprising:

determining an orientation of a robot relative to a chassis of a wafer processing system (see page 3, fig. 1 and col. 2); determining hand-off coordinates of a load port in the wafer processing system; and determining hand-off coordinates of a first load lock in the wafer processing system (see page 3, fig. 1 and col. 2 as noted above).

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With respect to claim 2, performing wafer mapping calibration using a load port fixture (see page 6, fig. 4); and performing a wafer centering calibration routine (see page 7,

col. 2, particularly 3rd paragraph). With respect to 6, wherein determining the hand-off coordinates of the first load lock in the wafer processing (see page 3, col. 2 – to – page 4 col. 1 and fig. 2) system comprises: determining a safe z-coordinate for entering the first load lock (see page 7, fig. 5); determining a wafer transfer plane (see page 4, fig. 2); and determining radial and theta coordinates for wafer hand-off (see page 4, col. 2, 3rd paragraph). With respect to claim 7, wherein determining the safe z-coordinate for entering the first load lock (see page 7, fig. 5 and page 8, fig. 6) comprises: using the robot to find a feature located outside the first load lock (see page 8, fig. 6). With respect to claim 8, wherein the wafer processing system comprises a chemical vapor deposition system (see page 8, fig. 5 and page 4, fig. 2, inherently the process chamber contains chemical vapor). With respect to claim 9, a plurality of wafer slots (see page 8, fig. 6); a first sensor having a beam configured along an axis that represents a wafer center (see page 5, col. 1, 2nd, paragraph); and a calibration disk (see page 8, fig. 5). With respect to claim 10, wherein the calibration disk includes a central hole through which the beam of the first sensor passes through (inherently, the disk contains a central hole wherein a beam may pass through, therefore this particular limitation has not considered as the inventive concept). With respect to claim 12,

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a flag for providing a z-axis reference (see page 4, col. 1, 2nd, paragraph, wherein signal has been considered as flag). With respect to claim 14, wherein the calibration fixture simulates a front-opening unified pod (FOUP) (see page 3, fig. 1, and col. 1, 4th, paragraph). With respect to claim 15, an interface port for allowing a sensor signal from

the calibration fixture to be coupled to a computer (see page 4, col. 1, 2nd, paragraph).

Allowable Subject Matter

- 4. Claims 16-20 are allowed.
- 5. The following is a statement of reasons for the indication of allowable subject matter:

The prior art of record fail to teach or fairly suggest the limitation of determining radial and theta locations in the calibration fixture in combination with the other elements of the claimed invention.

6. Claims 3-5, 11 and 13 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

7. The following is a statement of reasons for the indication of allowable subject matter:

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The prior art of record fail to teach or fairly suggest with respect to claim 3. determining a distance between the first sensor and the second sensor; and determining an offset between a coordinate frame of the robot and coordinate frame of

the wafer processing system with respect to claim 5, adjusting theta coordinates of locations in a load port fixture based on the orientation of the robot relative to the chassis of the wafer processing system; with respect to claim 11, wherein the calibration disk includes a surface simulating an edge of a wafer; with respect to claim 13, wherein the flag comprises a metallic disk in combination with the other elements of the claimed invention.

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to McDieunel Marc whose telephone number is (703) 305-4478. The examiner can normally be reached on 6:30-5:00 Mon-Thu.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Thomas Black can be reached on (703) 305-8233. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Thursday, October 14, 2004

MM/

THORNAS G. BLACK EXAMINER